Programmable logic sequencer (16 × 45 × 12)

PLS157

DESCRIPTION

The PLS157 is a 3-State output, registered logic element combining AND/OR gate arrays with clocked J-K flip-flops. These J-K flip-flops are dynamically convertible to D-type via a "fold-back" inverting buffer and control gate F_C. It features 6 registered I/O outputs (F) in conjunction with 6 bidirectional I/O lines (B). These yield variable I/O gate and register configurations via control gates (D, L) ranging from 16 inputs to 12 outputs.

The AND/OR arrays consist of 32 logic AND gates, 13 control AND gates, and 21 OR gates with fusible link connections for programming I/O polarity and direction. All AND gates are linked to 4 inputs (I), bidirectional I/O lines (B), internal flip-flop outputs (Q), and Complement Array output ($\overline{C}$). The Complement Array consists of a NOR gate optionally linked to all AND gates for generating and propagating complementary AND terms.

On-chip T/C buffers couple either True (I, B, Q) or Complement ($\overline{I}$, $\overline{B}$, $\overline{Q}$, $\overline{C}$) input polarities to all AND gates, whose outputs can be optionally linked to all OR gates. Any of the 32 AND gates drives bidirectional I/O lines (B), whose output polarity is individually programmable through a set of Ex-OR gates for implementing AND-OR or AND-NOR logic functions. Similarly, any of the 32 AND gates can drive the J-K inputs of all flip-flops. The Asynchronous Preset and Reset lines (P, R), are driven from the AND array for 4 of the 8 registers. The Preset and Reset lines (P, R) controlling the lower four registers are driven from the OR matrix.

All flip-flops are positive edge-triggered and can be used as input, output or I/O (for interfacing with a bidirectional data bus) in conjunction with load control gates (L), steering inputs (I), (B), (Q) and programmable output select lines (E).

The PLS157 is field programmable, enabling the user to quickly generate custom patterns using standard programming equipment.

Order codes are listed below.

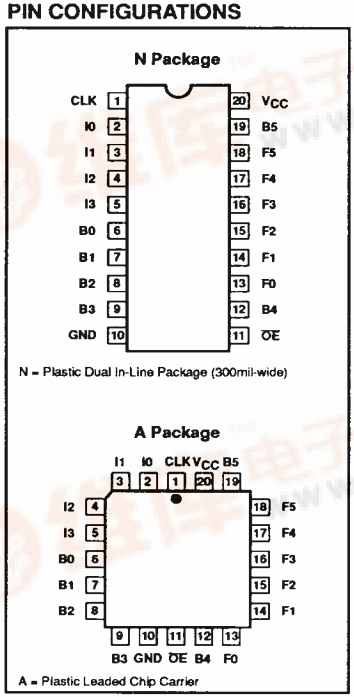
FEATURES

- f_{MAX} = 14MHz
  - 18.2MHz clock rate
- Field-Programmable (Ni-Cr link)
- 4 dedicated inputs
- 13 control gates
- 32 AND gates
- 21 OR gates
- 45 product terms:
  - 32 logic terms
  - 13 control terms
- 6 bidirectional I/O lines
- 6 bidirectional registers
- J-K, T, or D-type flip-flops
- 3-State outputs
- Asynchronous Preset/Reset
- Complement Array
- Active-High or -Low outputs
- Programmable $\overline{OE}$ control
- Positive edge-triggered clock
- Input loading: −100μA (max.)
- Power dissipation: 750mW (typ.)
- TTL compatible

APPLICATIONS

- Random sequential logic
- Synchronous up/down counters
- Shift registers
- Bidirectional data buffers
- Timing function generators
- System controllers/synchronizers
- Priority encoder/registers

PIN CONFIGURATIONS



N = Plastic Dual In-Line Package (300mil-wide)

A = Plastic Leaded Chip Carrier

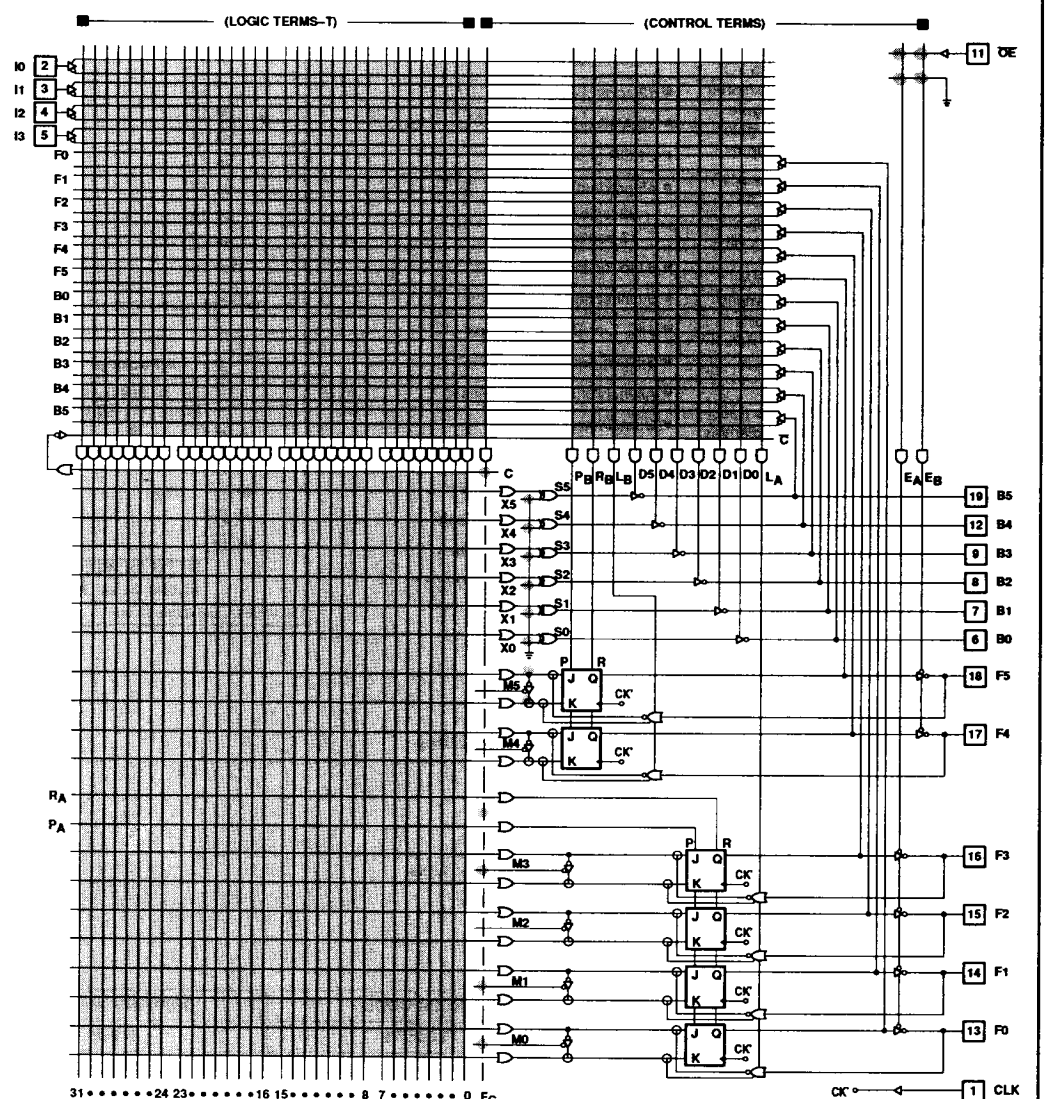
ORDERING INFORMATION

DESCRIPTION	ORDER CODE	DRAWING NUMBER
20-Pin Plastic Dual In-Line Package (300mil-wide)	PLS157N	0408B
20-Pin Plastic Leaded Chip Carrier	PLS157A	0400E

Programmable logic sequencer (16 × 45 × 12)

PLS157

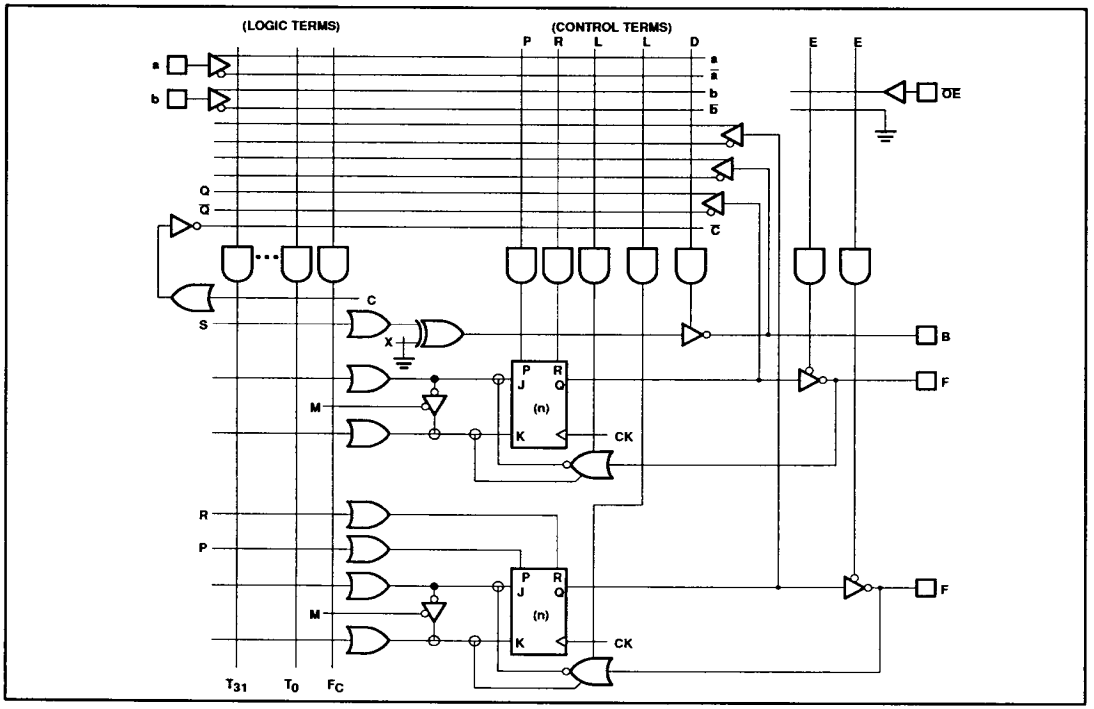
LOGIC DIAGRAM



NOTES:
1. All OR gate inputs with a blown link float to logic "0".
2. All other gates and control inputs with a blown link float to logic "1".
3. ⊕ denotes WIRE-OR.
4. ▒ Programmable connection.

Programmable logic sequencer (16 × 45 × 12) PLS157

FUNCTIONAL DIAGRAM

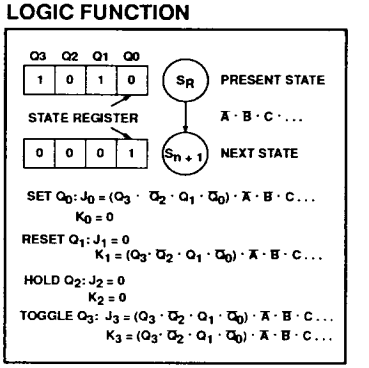


VIRGIN STATE

The factory shipped virgin device contains all fusible links intact, such that:

1. $\overline{OE}$ is always enabled.
2. Preset and Reset are always disabled.
3. All transition terms are disabled.
4. All flip-flops are in D-mode unless otherwise programmed to J-K only or J-K or D (controlled).
5. All B pins are inputs and all F pins are outputs unless otherwise programmed.

LOGIC FUNCTION



NOTE:
Similar logic functions are applicable for D and T mode flip-flops.

Programmable logic sequencer (16 × 45 × 12) — PLS157

FLIP-FLOP TRUTH TABLE

$\overline{OE}$	L	CK	P	R	J	K	Q	F
H								HI-Z
L	X	X	H	L	X	X	H	L
L	X	X	L	H	X	X	L	H
L	L	↑	L	L	L	L	Q	$\overline{Q}$
L	L	↑	L	L	L	H	L	H
L	L	↑	L	L	H	L	H	L
L	L	↑	L	L	H	H	$\overline{Q}$	Q
H	H	↑	L	L	L	H	L	H*
H	H	↑	L	L	H	L	H	L*
+10V	X	↑	X	X	L	H	L	H**
	X	↑	X	X	H	L	H	L**

NOTES:
1. Positive Logic: $J\text{-}K = T_0 + T_1 + T_2 \ldots\ldots\ldots\ldots T_{31}$
   $T_n = \overline{C} \cdot (I_0 \cdot I_1 \cdot I_2 \ldots) \cdot (Q_0 \cdot Q_1 \ldots) \cdot (B_0 \cdot B_1 \cdot \ldots)$
2. ↑ denotes transition from Low to High level.
3. X = Don't care
4. * = Forced at F_n pin for loading the J-K flip-flop in the Input mode. The load control term, L_n must be enabled (HIGH) and the p-terms that are connected to the associated flip-flop must be forced LOW (disabled) during Preload.
5. At P = R = H, Q = H. The final state of Q depends on which is released first.
6. ** = Forced at F_n pin to load J-K flip-flop independent of program code (Diagnostic mode), 3-State B outputs.

ABSOLUTE MAXIMUM RATINGS[1]

SYMBOL	PARAMETER	RATINGS MIN	RATINGS MAX	UNIT
V_{CC}	Supply voltage		+7	V_{DC}
V_{IN}	Input voltage		+5.5	V_{DC}
V_{OUT}	Output voltage		+5.5	V_{DC}
I_{IN}	Input currents	–30	+30	mA
I_{OUT}	Output currents		+100	mA
T_{amb}	Operating temperature range	0	+75	°C
T_{stg}	Storage temperature range	–65	+150	°C

NOTES:
1. Stresses above those listed may cause malfunction or permanent damage to the device. This is a stress rating only. Functional operation at these or any other condition above those indicated in the operational and programming specification of the device is not implied.

THERMAL RATINGS

TEMPERATURE	
Maximum junction	150°C
Maximum ambient	75°C
Allowable thermal rise ambient to junction	75°C

Programmable logic sequencer (16 × 45 × 12) — PLS157

DC ELECTRICAL CHARACTERISTICS

$0°C \leq T_{amb} \leq +75°C$, $4.75V \leq V_{CC} \leq 5.25V$

SYMBOL	PARAMETER	TEST CONDITION	LIMITS			UNIT
			MIN	TYP[1]	MAX	
Input voltage[2]						
V_{IH}	High	V_{CC} = MAX	2.0			V
V_{IL}	Low	V_{CC} = MIN			0.8	V
V_{IC}	Clamp	V_{CC} = MIN, I_{IN} = −12mA		−0.8	−1.2	V
Output voltage[2]						
		V_{CC} = MIN				
V_{OH}	High	I_{OH} = −2mA	2.4			V
V_{OL}	Low	I_{OL} = 10mA		0.35	0.5	V
Input current						
I_{IH}	High	V_{IN} = 5.5V		<1	80	µA
I_{IL}	Low	V_{IN} = 0.45V		−10	−100	µA
Output current						
		V_{CC} = MAX				
$I_{O(OFF)}$	Hi-Z state[5, 6]	V_{OUT} = 5.5V		1	80	µA
		V_{OUT} = 0.45V		−1	−140	µA
I_{OS}	Short circuit[3, 7]	V_{OUT} = 0V	−15		−70	mA
I_{CC}	V_{CC} supply current[4]	V_{CC} = MAX		150	190	mA
Capacitance						
		V_{CC} = 5.0V				
C_{IN}	Input	V_{IN} = 2.0V		8		pF
C_{OUT}	Output	V_{OUT} = 2.0V		15		pF

NOTES:
1. All typical values are at V_{CC} = 5V, T_{amb} = +25°C.
2. All voltage values are with respect to network ground terminal.
3. Test one at a time.
4. I_{CC} is measured with the $\overline{OE}$ input grounded, all other inputs at 4.5V and the outputs open.
5. Leakage values are a combination of input and output leakage.
6. Measured with V_{IH} applied to $\overline{OE}$.
7. Duration of short circuit should not exceed 1 second.

AC ELECTRICAL CHARACTERISTICS

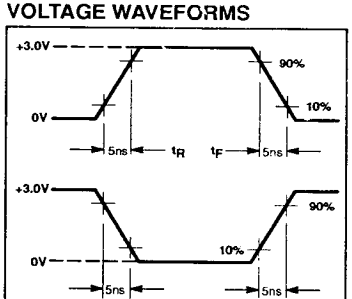
$0°C \leq T_{amb} \leq +75°C$, $4.75V \leq V_{CC} \leq 5.25V$, $R_1 = 470\Omega$, $R_2 = 1k\Omega$

SYMBOL	PARAMETER	FROM	TO	TEST CONDITION	LIMITS MIN	LIMITS TYP[1]	LIMITS MAX	UNIT
Pulse width								
t_{CKH}	Clock[2] High	CK +	CK –	C_L = 30pF	25	20		ns
t_{CKL}	Clock Low	CK –	CK +	C_L = 30pF	30	20		ns
t_{CKP}	Period	CK +	CK +	C_L = 30pF	70	50		ns
t_{PRH}	Preset/Reset pulse	(I,B) –	(I,B) +	C_L = 30pF	40	30		ns
Setup time[5]								
t_{IS1}	Input	(I,B) ±	CK +	C_L = 30pF	40	30		ns
t_{IS2}	Input (through F_n)	F ±	CK +	C_L = 30pF	20	10		ns
t_{IS3}	Input (through Complement Array)[4]	(I,B) ±	CK +	C_L = 30pF	65	40		ns
Hold time								
t_{IH1}	Input	(I,B) ±	CK +	C_L = 30pF	0	–10		ns
t_{IH2}	Input	F ±	CK +	C_L = 30pF	15	10		ns
Propagation delays								
t_{CKO}	Clock	CK +	F ±	C_L = 30pF		25	30	ns
t_{OE1}	Output enable[3]	$\overline{OE}$ –	F –	C_L = 30pF		20	30	ns
t_{OD1}	Output disable[3]	$\overline{OE}$ +	F +	C_L = 5pF		20	30	ns
t_{PD}	Output	(I,B) ±	B ±	C_L = 30pF		40	50	ns
t_{OE2}	Output enable[3]	(I,B) +	B ±	C_L = 30pF		35	55	ns
t_{OD2}	Output disable[3]	(I,B) –	B +	C_L = 5pF		30	35	ns
t_{PRO}	Preset/Reset	(I,B) +	F ±	C_L = 30pF		50	55	ns

NOTES:

1. All typical values are at V_{CC} = 5V, T_{amb} = +25°C.
2. To prevent spurious clocking, clock rise time (10% – 90%) ≤ 10ns.
3. For 3-State output; output enable times are tested with C_L = 30pF to the 1.5V level, and S_1 is open for high-impedance to High tests and closed for high-impedance to Low tests. Output disable times are tested with C_L = 5pF. High-to-High impedance tests are made to an output voltage of $V_T = (V_{OH} - 0.5V)$ with S_1 open, and Low-to-High impedance tests are made to the $V_T = (V_{OL} + 0.5V)$ level with S_1 closed.
4. When using the Complement Array t_{CKP} = 95ns (min).
5. Limits are guaranteed with 12 product terms maximum connected to each sum term line.

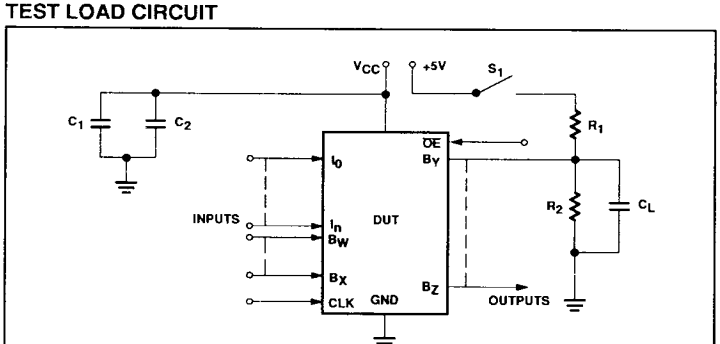
VOLTAGE WAVEFORMS



MEASUREMENTS:
All circuit delays are measured at the +1.5V level of inputs and outputs, unless otherwise specified.

Input Pulses

TEST LOAD CIRCUIT



NOTE:
C_1 and C_2 are to bypass V_{CC} to GND.

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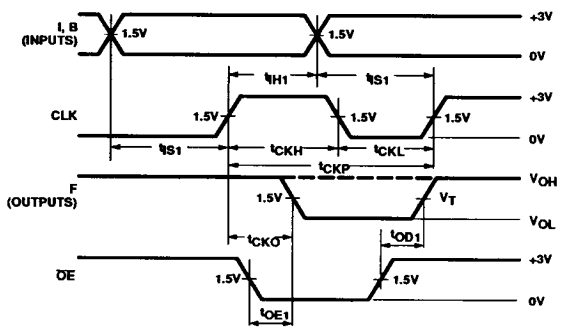
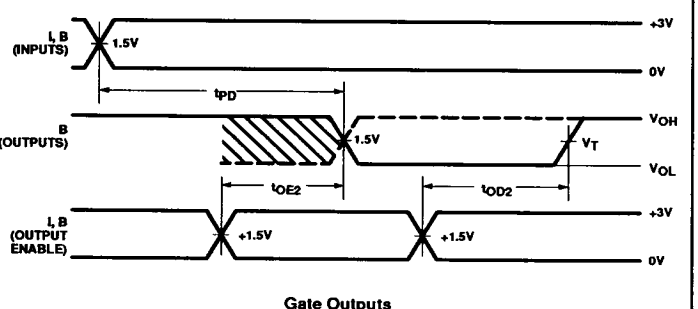
TIMING DIAGRAMS



Flip-Flop Outputs

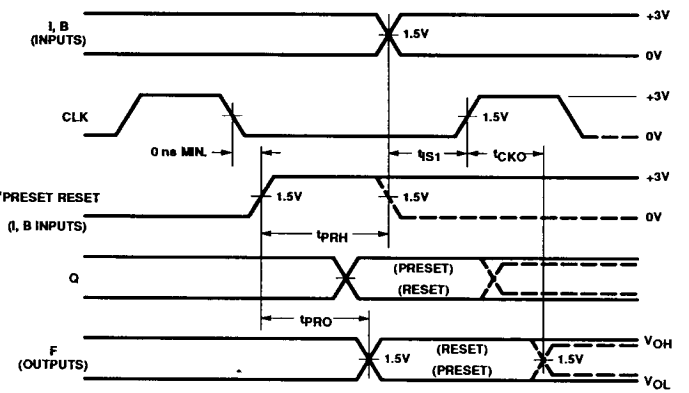


Gate Outputs

TIMING DEFINITIONS

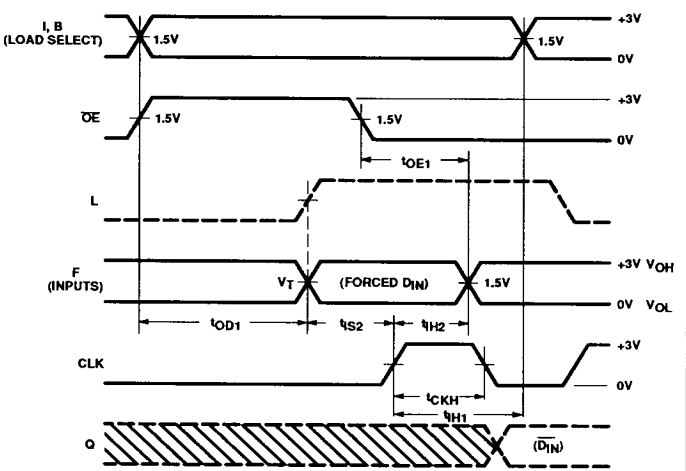
SYMBOL	PARAMETER
t_{CKH}	Width of input clock pulse.
t_{CKL}	Interval between clock pulses.
t_{CKP}	Clock period.
t_{PRH}	Width of preset input pulse.
t_{IS1}	Required delay between beginning of valid input and positive transition of clock.
t_{IS2}	Required delay between beginning of valid input forced at flip-flop output pins, and positive transition of clock.
t_{IH1}	Required delay between positive transition of clock and end of valid input data.
t_{IH2}	Required delay between positive transition of clock and end of valid input data forced at flip-flop output pins.
t_{CKO}	Delay between positive transition of clock and when outputs become valid (with $\overline{OE}$ Low).
t_{OE1}	Delay between beginning of Output Enable Low and when outputs become valid.
t_{OD1}	Delay between beginning of Output Enable High and when outputs are in the OFF-State.
t_{PD}	Propagation delay between combinational inputs and outputs.
t_{OE2}	Delay between predefined Output Enable High, and when combinational outputs become valid.
t_{OD2}	Delay between predefined Output Enable Low and when combinational outputs are in the OFF-State.
t_{PRO}	Delay between positive transition of predefined Preset/Reset input, and when flip-flop outputs become valid.

TIMING DIAGRAMS (Continued)



* The leading edge of preset/reset must occur only when the input clock is "low", and must remain "high" as long as required to override clock. The falling edge of preset/reset can never go "low" when the input clock is "high".

Asynchronous Preset/Reset



Flip-Flop Input Mode

Programmable logic sequencer (16 × 45 × 12)

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LOGIC PROGRAMMING

The PLS157 is fully supported by industry standard (JEDEC compatible) PLD CAD tools, including Philips Semiconductors' SNAP, Data I/O Corporation's ABEL™ and Logical Devices Inc.'s CUPL™ design software packages.

All packages allow Boolean and state equation entry formats. SNAP, ABEL and CUPL also accept, as input, schematic capture format.

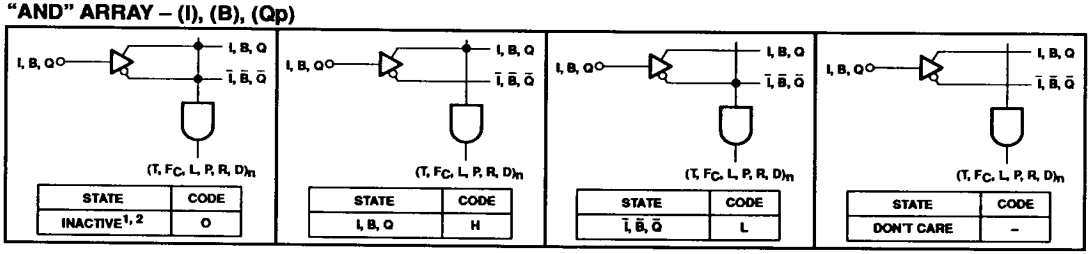
PLS157 logic designs can also be generated using the program table entry format detailed on the following pages. This program table entry format is supported by the Philips Semiconductors SNAP PLD design software package only.

To implement the desired logic functions, the state of each logic variable from logic equations (I, B, O, P, etc.) is assigned a symbol. The symbols for TRUE, COMPLEMENT, INACTIVE, PRESET, etc., are defined below.

PROGRAMMING AND SOFTWARE SUPPORT

Refer to Section 9 *(Development Software)* and Section 10 *(Third-party Programmer/ Software Support)* of this data handbook for additional information.

"AND" ARRAY – (I), (B), (Qp)



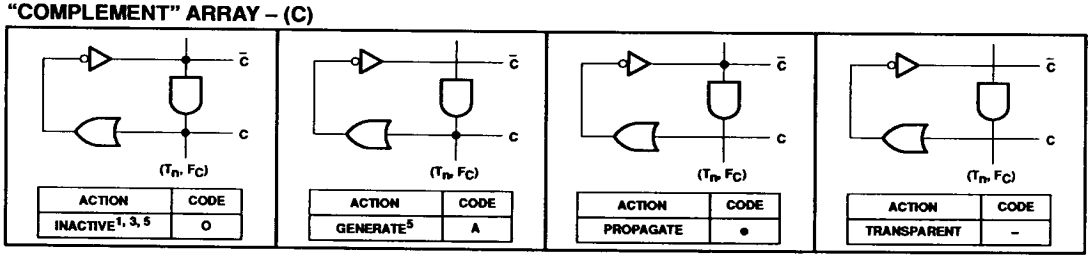
STATE	CODE
INACTIVE[1, 2]	O

STATE	CODE
I, B, Q	H

STATE	CODE
Ī, B̄, Q̄	L

STATE	CODE
DON'T CARE	–

"COMPLEMENT" ARRAY – (C)



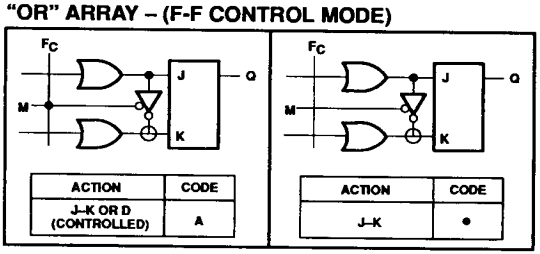
ACTION	CODE
INACTIVE[1, 3, 5]	O

ACTION	CODE
GENERATE[5]	A

ACTION	CODE
PROPAGATE	•

ACTION	CODE
TRANSPARENT	–

"OR" ARRAY – (F-F CONTROL MODE)



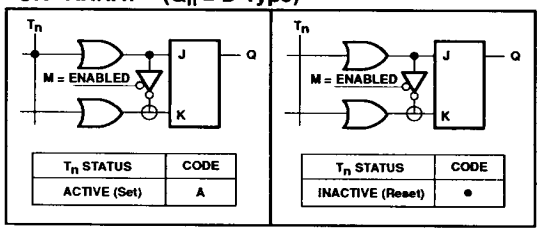
ACTION	CODE
J–K OR D (CONTROLLED)	A

ACTION	CODE
J–K	•

Notes on following page.

Programmable logic sequencer (16 × 45 × 12) — PLS157

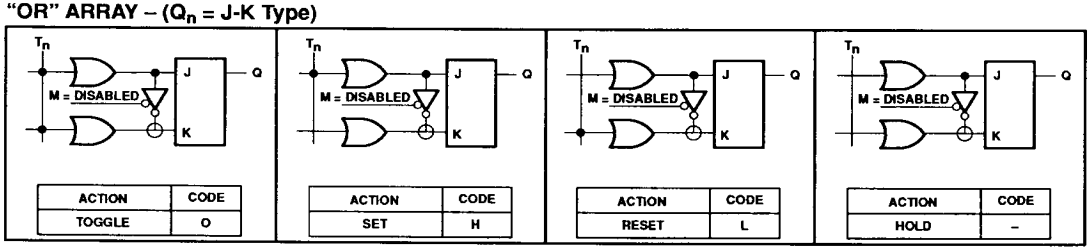
"OR" ARRAY – (Q_n = D-Type)



T_n STATUS	CODE
ACTIVE (Set)	A

T_n STATUS	CODE
INACTIVE (Reset)	•

"OR" ARRAY – (Q_n = J-K Type)



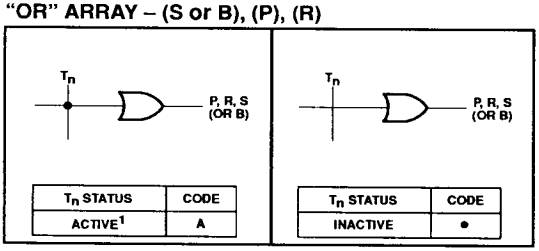
ACTION	CODE
TOGGLE	O

ACTION	CODE
SET	H

ACTION	CODE
RESET	L

ACTION	CODE
HOLD	–

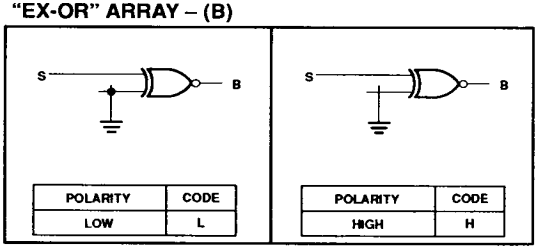
"OR" ARRAY – (S or B), (P), (R)



T_n STATUS	CODE
ACTIVE[1]	A

T_n STATUS	CODE
INACTIVE	•

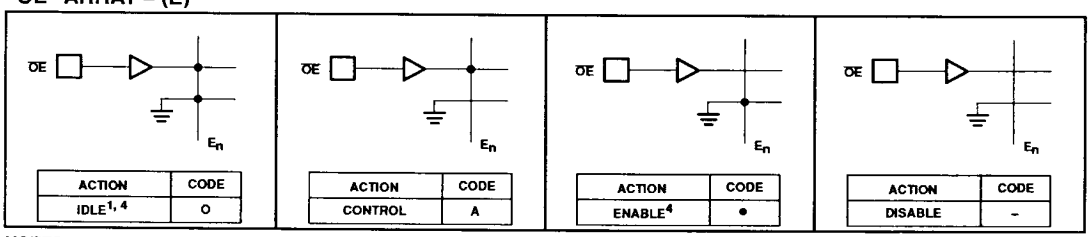
"EX-OR" ARRAY – (B)



POLARITY	CODE
LOW	L

POLARITY	CODE
HIGH	H

"$\overline{OE}$" ARRAY – (E)



ACTION	CODE
IDLE[1, 4]	O

ACTION	CODE
CONTROL	A

ACTION	CODE
ENABLE[4]	•

ACTION	CODE
DISABLE	–

NOTES:
1. This is the initial unprogrammed state of all link pairs. It is normally associated with all unused (inactive) AND gates.
2. Any gate ($T, F_C, L, P, R, D)_n$ will be unconditionally inhibited if both of the I, B, or Q links are left intact.
3. To prevent oscillations, this state is not allowed for C link pairs coupled to active gates T_n, F_C.
4. E_n = O and E_n = • are logically equivalent states, since both cause F_n outputs to be unconditionally enabled.
5. These states are not allowed for control gates $(L, P, R, D)_n$ due to their lack of "OR" array links.

Programmable logic sequencer (16 × 45 × 12)

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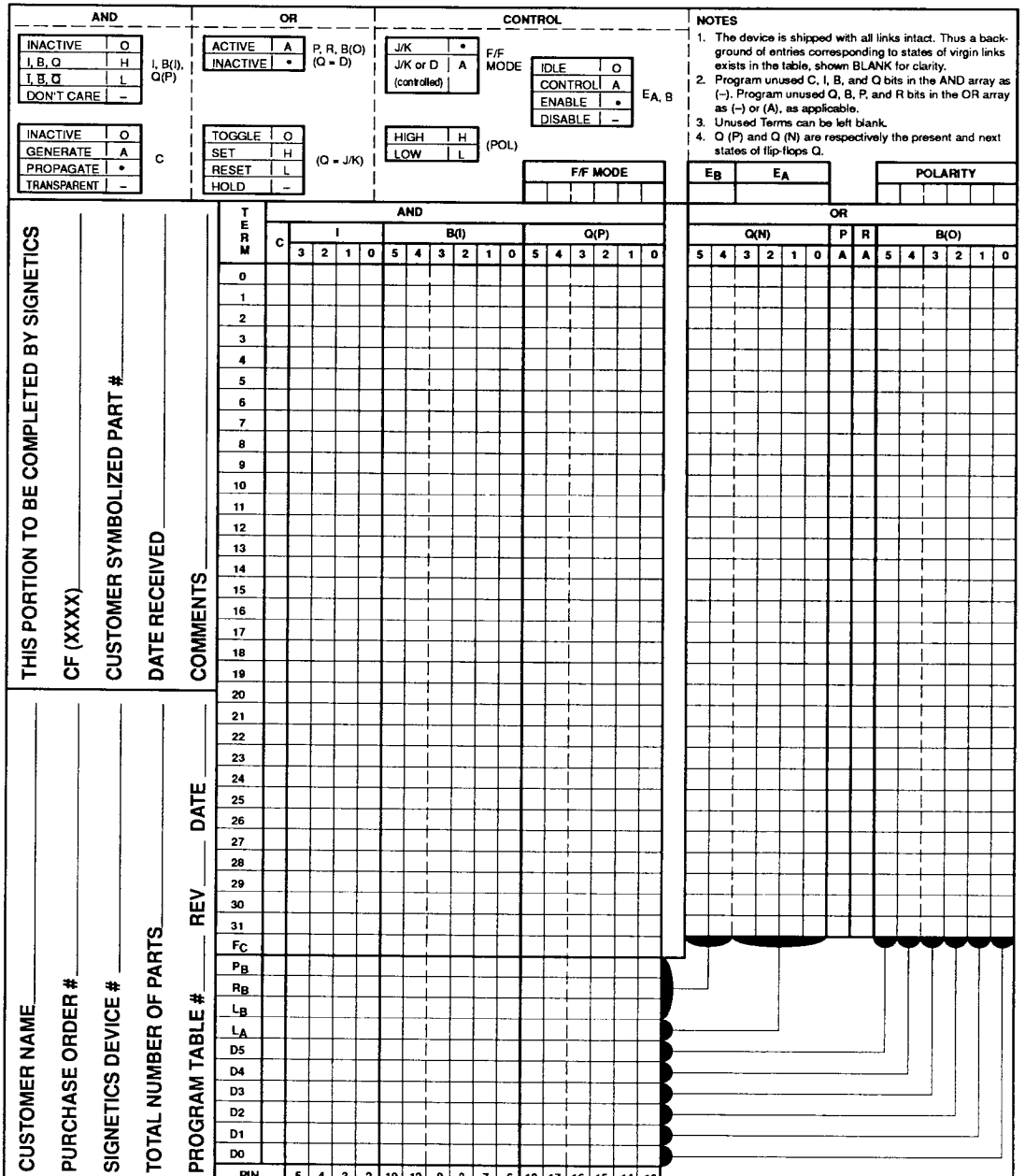
PROGRAM TABLE



Programmable logic sequencer (16 × 45 × 12) — PLS157

SNAP RESOURCE SUMMARY DESIGNATIONS